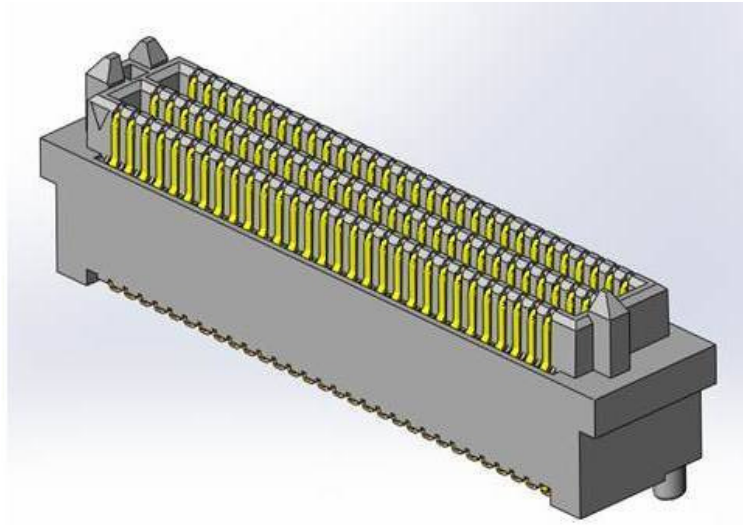
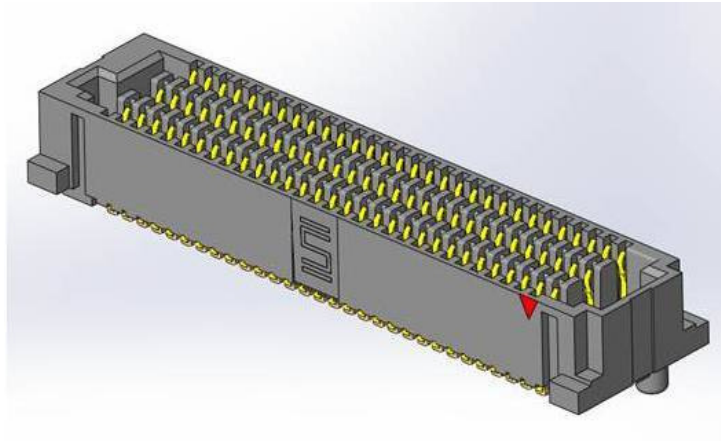




| | |
|---|------------------------------------|
| Project Number: Design Qualification Test Report | Tracking Code: 251496_Report_Rev_1 |
| Requested by: Catie Eichhorn | Date: 8/15/2013 |
| Part #: SEAF8-30-05.0-S-06-2/SEAM8-30-S05.0-S-06-2-K-TR | |
| Part description: SEAF8/SEAM8 | Tech: Kason He |
| Test Start: 05/28/2013 | Test Completed: 06/25/2013 |



DESIGN QUALIFICATION TEST REPORT

SEAF8/SEAM8

SEAF8-30-05.0-S-06-2/SEAM8-30-S05.0-S-06-2-K-TR

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

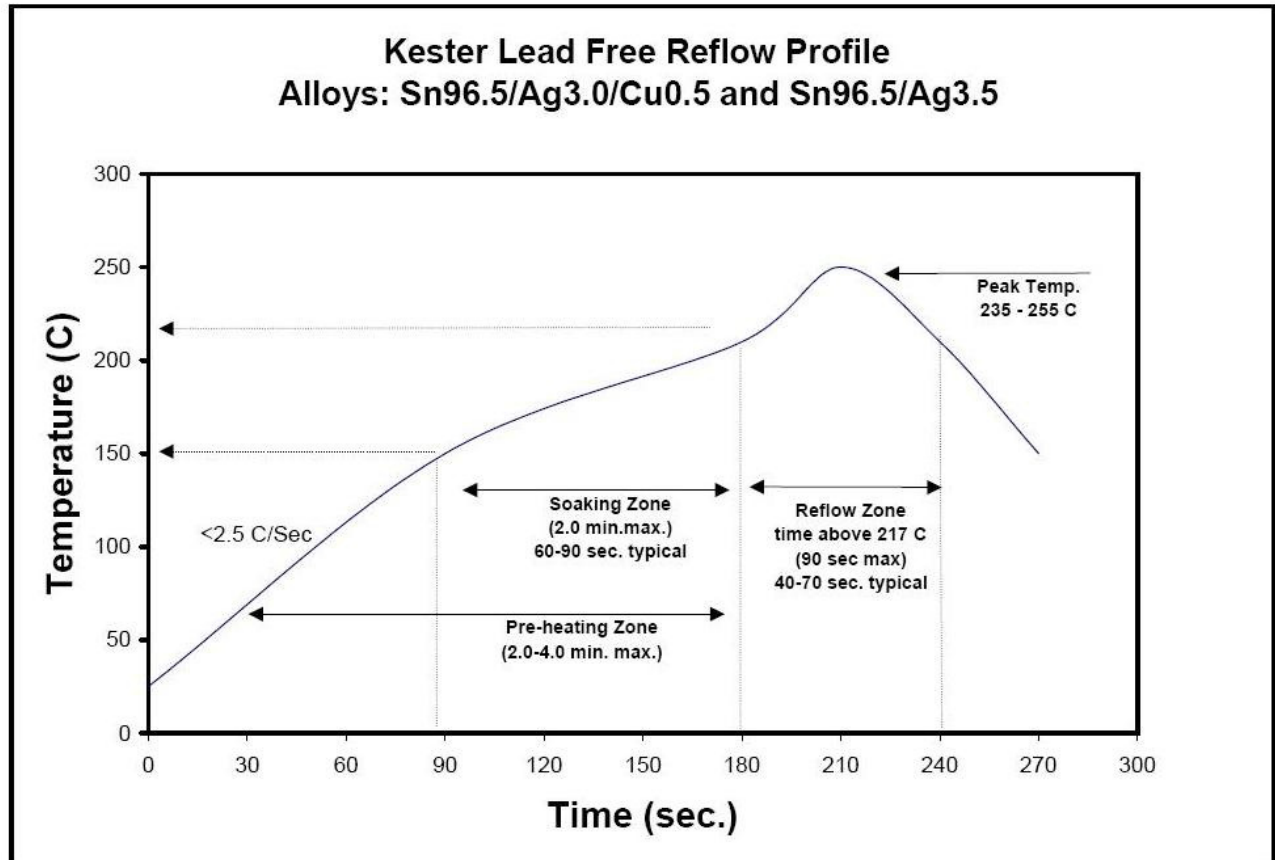
To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.
- 10) Samtec Test PCBs used: PCB-104011-TST

TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)

FLOWCHARTS**Extended Life**

| TEST STEP | GROUP 1 8 Assemblies 100 Cycles | GROUP 2 8 Assemblies 250 Cycles | GROUP 3 8 Assemblies 500 Cycles | GROUP 4 8 Assemblies 1,000 Cycles |
|------------------|--|--|--|--|
| 01 | * Plating Thickness Verification | * Plating Thickness Verification | * Plating Thickness Verification | * Plating Thickness Verification |
| 02 | LLCR-1 | LLCR-1 | LLCR-1 | LLCR-1 |
| 03 | 100 Cycles | 250 Cycles | 500 Cycles | 1,000 Cycles |
| 04 | Clean Mating Interface | Clean Mating Interface | Clean Mating Interface | Clean Mating Interface |
| 05 | LLCR-2 | LLCR-2 | LLCR-2 | LLCR-2 |
| 06 | Thermal Shock (Mated and undisturbed) | Thermal Shock (Mated and undisturbed) | Thermal Shock (Mated and undisturbed) | Thermal Shock (Mated and undisturbed) |
| 07 | LLCR-3 | LLCR-3 | LLCR-3 | LLCR-3 |
| 08 | Cyclic Humidity (Mated and undisturbed) | Cyclic Humidity (Mated and undisturbed) | Cyclic Humidity (Mated and undisturbed) | Cyclic Humidity (Mated and undisturbed) |
| 09 | LLCR-4 | LLCR-4 | LLCR-4 | LLCR-4 |
| 10 | *** Photos of Contact Area | *** Photos of Contact Area | *** Photos of Contact Area | *** Photos of Contact Area |

Thermal Shock = EIA-364-32, Table II, Test Condition I:

-55°C to +85°C 1/2 hour dwell, 100 cycles

Humidity = EIA-364-31, Test Condition 'B' (240 Hours)

and Method III (+25°C to +65°C @ 90% RH to 98% RH)

ambient pre-condition and delete steps 7a and 7b

LLCR = EIA-364-23, LLCR

20 mV Max, 100 mA Max

Use Keithley 580 or 3706 in 4 wire dry circuit mode

* Measure, verify, and document plating thickness on both male and female (one group only)

** Plating thickness to be measured on loose pins used during assembly. Pins to be provided by requestor.

*** Save 2-3 photos of contact area in project folder for each group

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

LLCR:

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms:----- Stable
 - b. $+5.1$ to $+10.0$ mOhms:----- Minor
 - c. $+10.1$ to $+15.0$ mOhms:----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms:----- Marginal
 - e. $+50.1$ to $+2000$ mOhms:----- Unstable
 - f. $>+2000$ mOhms:----- Open Failure

RESULTS**LLCR Durability 100 cycles: (192 points)**

- **Initial** ----- 21.00mOhms Max
- **Durability, 100 Cycles**
 - <= +5.0 mOhms ----- 192 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 192 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 184 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 8 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

LLCR Durability 250 cycles: (192 points)

- **Initial** ----- 20.48mOhms Max
- **Durability, 250 Cycles**
 - <= +5.0 mOhms ----- 192 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 192 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 178 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 14 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

RESULTS Continued**LLCR Durability 500 cycles: (192 points)**

- **Initial** ----- 18.91mOhms Max
- **Durability, 500 Cycles**
 - <= +5.0 mOhms ----- 192 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 192 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 186 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 6 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

LLCR Durability 1000 cycles: (192 points)

- **Initial** ----- 20.24mOhms Max
- **Durability, 1000 Cycles**
 - <= +5.0 mOhms ----- 192 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Thermal**
 - <= +5.0 mOhms ----- 192 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure
- **Humidity**
 - <= +5.0 mOhms ----- 190 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 2 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
 - >+2000 mOhms ----- 0 Points ----- Open Failure

DATA SUMMARIES**LLCR Durability 100 cycles:**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

| LLCR Measurement Summaries by Pin Type | | | | |
|---|----------------|-------------------|-------------------------|-----------------------|
| Date | 2013-5-28 | 2013-5-28 | 2013-6-5 | 2013-6-25 |
| Room Temp (Deg C) | 23 | 23 | 22 | 24 |
| Rel Humidity (%) | 60 | 58 | 58 | 55 |
| Technician | Kason He | Kason He | Kason He | Kason He |
| mOhm values | Actual | Delta | Delta Therm Shck | Delta Humidity |
| | Initial | 100 Cycles | | |
| Pin Type 1: Signal | | | | |
| Average | 16.97 | 0.70 | 0.76 | 1.25 |
| St. Dev. | 1.01 | 0.74 | 0.77 | 1.52 |
| Min | 15.45 | 0.00 | 0.01 | 0.00 |
| Max | 21.00 | 4.73 | 4.48 | 8.15 |
| Summary Count | 192 | 192 | 192 | 192 |
| Total Count | 192 | 192 | 192 | 192 |

| LLCR Delta Count by Category | | | | | | |
|-------------------------------------|---------------|--------------------------|---------------------------|---------------------------|-----------------------------|-------------|
| | Stable | Minor | Acceptable | Marginal | Unstable | Open |
| mOhms | ≤ 5 | $>5 \text{ \& } \leq 10$ | $>10 \text{ \& } \leq 15$ | $>15 \text{ \& } \leq 50$ | $>50 \text{ \& } \leq 1000$ | >1000 |
| 100 Cycles | 192 | 0 | 0 | 0 | 0 | 0 |
| Therm Shck | 192 | 0 | 0 | 0 | 0 | 0 |
| Humidity | 184 | 8 | 0 | 0 | 0 | 0 |

DATA SUMMARIES Continued**LLCR Durability 250 cycles:**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

| LLCR Measurement Summaries by Pin Type | | | | |
|---|-----------------------|-------------------------|-------------------------|-----------------------|
| Date | 2013-5-28 | 2013-5-29 | 2013-6-5 | 2013-6-25 |
| Room Temp (Deg C) | 23 | 25 | 22 | 24 |
| Rel Humidity (%) | 60 | 60 | 58 | 55 |
| Technician | kason he | kason he | Kason He | Kason He |
| mOhm values | Actual Initial | Delta 250 Cycles | Delta Therm Shck | Delta Humidity |
| Pin Type 1: Signal | | | | |
| Average | 17.01 | 0.64 | 0.70 | 1.26 |
| St. Dev. | 0.69 | 0.55 | 0.73 | 1.61 |
| Min | 15.69 | 0.00 | 0.00 | 0.00 |
| Max | 20.48 | 3.30 | 4.43 | 7.11 |
| Summary Count | 192 | 192 | 192 | 192 |
| Total Count | 192 | 192 | 192 | 192 |

| LLCR Delta Count by Category | | | | | | |
|-------------------------------------|----------|------------------|-------------------|-------------------|---------------------|---------|
| mOhms | Stable | Minor | Acceptable | Marginal | Unstable | Open |
| | ≤ 5 | >5 & ≤ 10 | >10 & ≤ 15 | >15 & ≤ 50 | >50 & ≤ 1000 | >1000 |
| 250 Cycles | 192 | 0 | 0 | 0 | 0 | 0 |
| Therm Shck | 192 | 0 | 0 | 0 | 0 | 0 |
| Humidity | 178 | 14 | 0 | 0 | 0 | 0 |

DATA SUMMARIES Continued**LLCR Durability 500 cycles:**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

| LLCR Measurement Summaries by Pin Type | | | | |
|---|-----------------------|-------------------------|-------------------------|-----------------------|
| Date | 2013-5-29 | 2013-5-30 | 2013-6-5 | 2013-6-25 |
| Room Temp (Deg C) | 25 | 23 | 22 | 24 |
| Rel Humidity (%) | 60 | 60 | 58 | 55 |
| Technician | kason he | kason he | Kason He | Kason He |
| mOhm values | Actual Initial | Delta 500 Cycles | Delta Therm Shck | Delta Humidity |
| Pin Type 1: Signal | | | | |
| Average | 16.64 | 0.57 | 0.68 | 1.26 |
| St. Dev. | 0.58 | 0.43 | 0.65 | 1.46 |
| Min | 15.58 | 0.00 | 0.01 | 0.01 |
| Max | 18.91 | 2.12 | 3.35 | 8.84 |
| Summary Count | 192 | 192 | 192 | 192 |
| Total Count | 192 | 192 | 192 | 192 |

| LLCR Delta Count by Category | | | | | | |
|-------------------------------------|----------|------------------|-------------------|-------------------|---------------------|---------|
| mOhms | Stable | Minor | Acceptable | Marginal | Unstable | Open |
| | ≤ 5 | >5 & ≤ 10 | >10 & ≤ 15 | >15 & ≤ 50 | >50 & ≤ 1000 | >1000 |
| 500 Cycles | 192 | 0 | 0 | 0 | 0 | 0 |
| Therm Shck | 192 | 0 | 0 | 0 | 0 | 0 |
| Humidity | 186 | 6 | 0 | 0 | 0 | 0 |

DATA SUMMARIES Continued**LLCR Durability 1000 cycles:**

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: ----- Stable
 - b. $+5.1$ to $+10.0$ mOhms: ----- Minor
 - c. $+10.1$ to $+15.0$ mOhms: ----- Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: ----- Marginal
 - e. $+50.1$ to $+2000$ mOhms ----- Unstable
 - f. $>+2000$ mOhms: ----- Open Failure

| LLCR Measurement Summaries by Pin Type | | | | |
|---|-----------------------|--------------------------|-------------------------|-----------------------|
| Date | 2013-5-30 | 2013-6-1 | 2013-6-7 | 2013-6-25 |
| Room Temp (Deg C) | 23 | 23 | 22 | 24 |
| Rel Humidity (%) | 60 | 60 | 59 | 56 |
| Technician | kason he | kason he | Kason He | Kason He |
| mOhm values | Actual Initial | Delta 1000 Cycles | Delta Therm Shck | Delta Humidity |
| Pin Type 1: Signal | | | | |
| Average | 16.80 | 0.70 | 0.77 | 1.24 |
| St. Dev. | 0.86 | 0.67 | 0.69 | 1.08 |
| Min | 15.45 | 0.01 | 0.01 | 0.01 |
| Max | 20.24 | 3.83 | 3.44 | 5.86 |
| Summary Count | 192 | 192 | 192 | 192 |
| Total Count | 192 | 192 | 192 | 192 |

| LLCR Delta Count by Category | | | | | | |
|-------------------------------------|----------|------------------|-------------------|-------------------|---------------------|---------|
| mOhms | Stable | Minor | Acceptable | Marginal | Unstable | Open |
| | ≤ 5 | >5 & ≤ 10 | >10 & ≤ 15 | >15 & ≤ 50 | >50 & ≤ 1000 | >1000 |
| 1000 Cycles | 192 | 0 | 0 | 0 | 0 | 0 |
| Therm Shck | 192 | 0 | 0 | 0 | 0 | 0 |
| Humidity | 190 | 2 | 0 | 0 | 0 | 0 |

EQUIPMENT AND CALIBRATION SCHEDULES**Equipment #:** HZ-TCT-01**Description:** Normal force analyzer**Manufacturer:** Mecmesin Multitester**Model:** Mecmesin Multitester 2.5-i**Serial #:** 08-1049-04**Accuracy:** Last Cal: 4/26/2013, Next Cal: 4/25/2014**Equipment #:** HZ-MO-05**Description:** Micro-ohmmeter**Manufacturer:** Keithley**Model:** 3706**Serial #:** 1285188**Accuracy:** Last Cal: 11/15/2012, Next Cal: 11/14/2013